

TI Designs: TIDA-01442

采用 ADC12DJ3200 且适用于 L、S、C 和 X 频带的直接射频采样雷达接收器参考设计



TEXAS INSTRUMENTS

说明

TIDA-01442 TI 设计利用 ADC12DJ3200 EVM 演示直接射频采样接收器，适用于在 HF、VHF、UHF L、S、C 和部分 X 频带上运行的雷达。模数转换器 (ADC) 的宽模拟输入带宽和高采样率 (6.4GSPS) 可为单接收器或 ADC 提供多频带覆盖。该 ADC 具有直接射频采样功能，取消了对多个降频转换级的需求，减少了组件数量，因此降低了系统整体的复杂性。

资源

| | |
|-----------------------------|-------|
| TIDA-01442 | 设计文件夹 |
| ADC12DJ3200 | 产品文件夹 |
| LMK04828 | 产品文件夹 |
| LMX2582 | 产品文件夹 |
| TSW14J57EVM | 产品文件夹 |



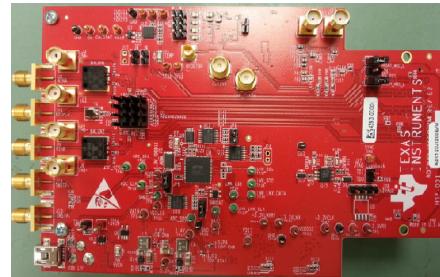
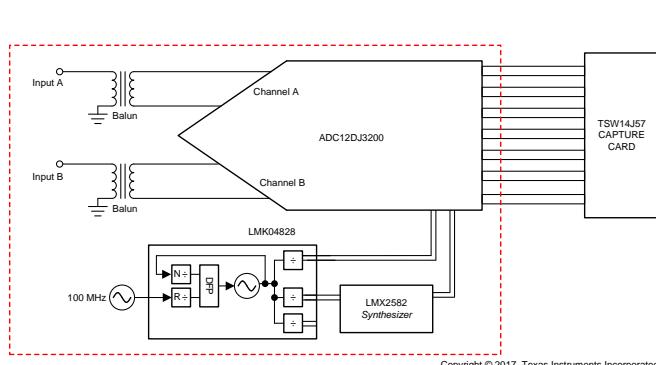
咨询我们的 E2E 专家

特性

- ADC 的高输入频率功能允许对从 L 频带到 X 频带的信号进行射频采样
- 单通道（交错模式）下的最大采样率为 6.4GSPS，双通道模式下的最大采样率为 3.2GSPS
- 每个 DDC 都具有四个独立的 NCO，可在多个频带中实现快速跳频
- 针对低抖动和 JESD204B 运行而优化的时钟解决方案

应用

- 军用雷达
- 气象雷达
- 空中交通控制雷达
- 测试和测量



该 TI 参考设计末尾的重要声明表述了授权使用、知识产权问题和其他重要的免责声明和信息。

1 System Description

The TIDA-01442 reference design demonstrates an AC-coupled, dual-channel wideband digitizer used for radar receiver applications. This design is based on the dual-channel, 12-bit, 3.2-GSPS ADC12DJ3200. Both channel A and channel B are AC coupled using a 9-GHz bandwidth balun. This design showcases the high sample rate 6.4 GSPS and wide bandwidth capabilities of the ADC12DJ3200. Both input channels have been optimized for wide bandwidth performance. This design focuses on demonstrating the performance of the device over 9 GHz of bandwidth in addition to discussing clocking and power management.

1.1 Key System Specifications

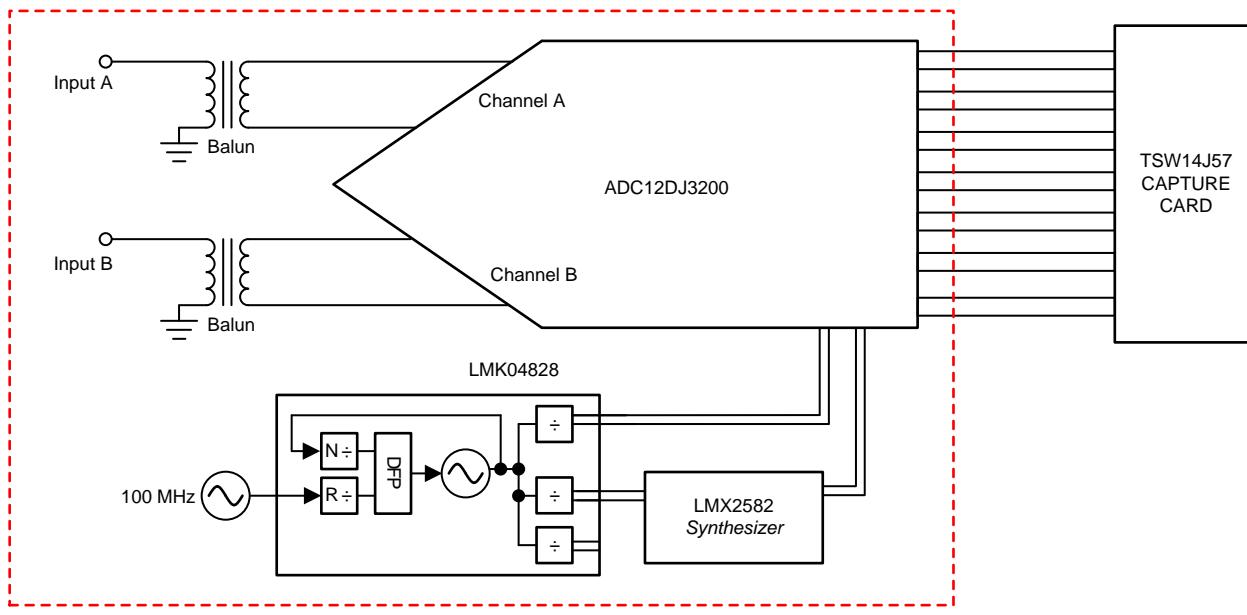
表 1. Key System Specifications

| PARAMETER | SPECIFICATIONS |
|-------------------------------|--|
| Analog input signal bandwidth | 9 GHz |
| Resolution | 12 bit |
| Max sampling rate | 6.4 GSPS in single channel interleaved and 3.2 GSPS in dual-channel input mode |
| Number of channels | 2 |
| SNR | > 44 dBFS across full bandwidth |
| Harmonic distortion | < -46 dBFS HD2/HD3 across full bandwidth |

2 System Overview

2.1 Block Diagram

图 1 shows the block diagram for the TIDA-01442 reference design. As the figure shows, a single-ended input signal can be applied at each input channel. The single-ended input signal is converted to a differential signal with a 9-GHz bandwidth balun. Both input paths can also be modified to accept differential input signals. The clocking for ADC is also implemented on the evaluation module (EVM). LMX2582 is used for clocking the ADC and LMK04828 is used for providing the SYSREF signal for the ADC and field-programmable gate array (FPGA), along with any additional clocking required by the FPGA.



Copyright © 2017, Texas Instruments Incorporated

图 1. TIDA-01442 Block Diagram

2.2 **Highlighted Products**

2.2.1 **ADC12DJ3200**

The ADC12DJxx00 family are RF-sampling gigasample ADCs that can directly sample input frequencies from DC to above 9 GHz. In dual-channel mode, the ADC12DJ3200, ADC12DJ2700, and ADC12DJ1600 can sample up to 3200 MSPS, 2700 MSPS or 1600 MSPS. In single-channel mode, the devices can sample up to 6400 MSPS, 5400 MSPS, or 3200 MSPS, respectively. With a –3-dB input bandwidth exceeding 9 GHz in either dual- or single-channel mode, the ADC12DJ3200/2700/1600 can be used to sample signals in the first, second, and higher Nyquist zones.

ADC12DJxx00s use a high-speed JESD204B output interface with up to 16 serialized lanes and support subclass-1 for deterministic latency and multi-device synchronization. The serial output lanes support up to 12.8 Gbps and can be configured to trade off bit rate versus number of lanes. In dual-channel mode, optional digital-down converters can tune and decimate a band from RF to a complex baseband signal to reduce the interface data rate in bandwidth-limited applications.

2.2.2 **LMK04828**

The LMK0482x family is the industry's highest-performance clock conditioner with JEDEC JESD204B support. The 14 clock outputs from PLL2 can be configured to drive seven JESD204B converters or other logic devices using device and SYSREF clocks. SYSREF can be provided using both DC and AC coupling. This device is available in a 64-pin QFN package (9 mm × 9 mm).

2.2.3 **LMX2582**

The LMX2582 is a low-noise, wideband RF phase-locked loop (PLL) with integrated VCO that supports a frequency range from 20 MHz to 5.5 GHz. The device supports both fractional-N and integer-N modes with a 32-bit fractional divider allowing fine frequency selection. Integrated noise of 47 fs for a 1.8-GHz output allows for an ideal low-noise source. The device is available in a 40-pin WQFN (6 mm × 6 mm).

3 System Design Theory

3.1 Clocking

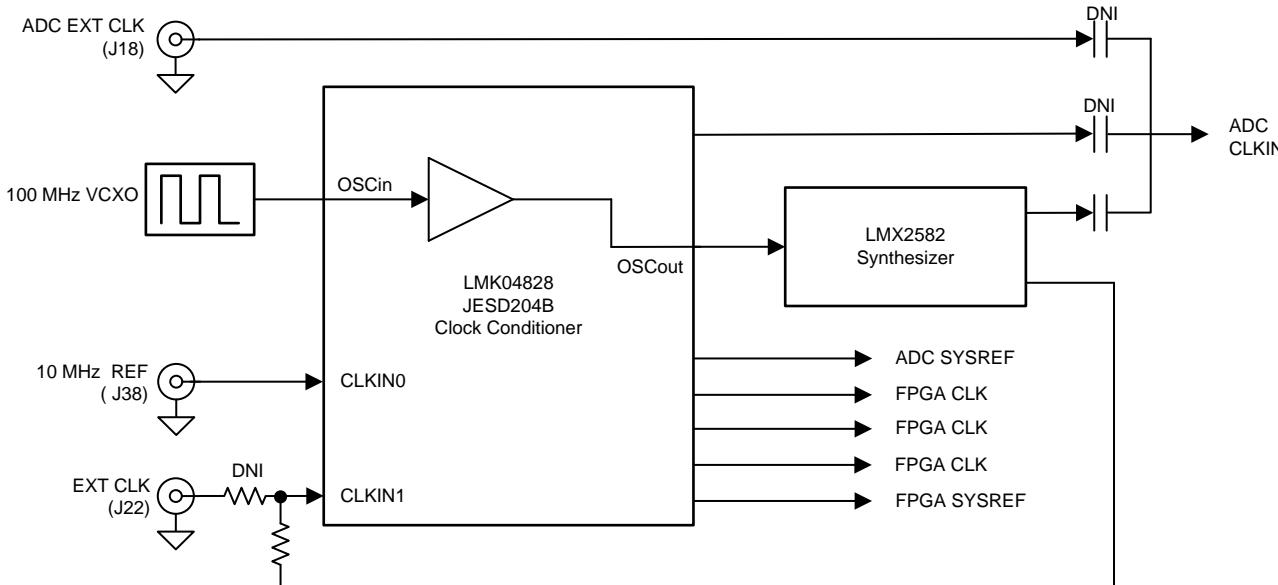
图 2 shows a block diagram of the clocking subsystem, which comprises an LMK04828 JESD204B clock conditioner, LMX2582 synthesizer, 100-MHz voltage-controlled crystal oscillator (VCXO), ADC, and LMK SMA clock inputs. The two main ways to clock the ADC are onboard clocking and external clocking.

Onboard clocking:

- By default, the ADC12DJ3200EVM is set up to use onboard clocking. When using the default onboard clocking option for the ADC EVM, the LMX2582 is used as a clock source for the ADC and LMK04828 is used for providing the SYSREF for the ADC and the FPGA, in addition to being used for clocking the FPGA. The VCXO is used as a reference for both LMK04828 and LMX2582. In this mode, there is an option to lock the VCXO to an external source by providing a 10-MHz reference clock to connector J38.

External clocking:

- If external clocking is desired, the clock from the external signal generator is provided to the ADC EXT CLK (J18) input connector and LMK EXT CLK (J22) connector. The LMK04828 device is used to provide the SYSREF and CLK to the FPGA as well as the SYSREF to ADC. In external clock mode, the LMX2582 is powered down. When using external clocking mode, C49 and C52 must be installed and C48, C50, C51, and C53 must be uninstalled.



Copyright © 2017, Texas Instruments Incorporated

图 2. Clocking

3.2 Power

This ADC12DJ3200EVM operates from a single +5-V power supply, which powers a combination of switching and linear regulators that are used to power the various domains on the board. 图 3 shows a block diagram of the power management.

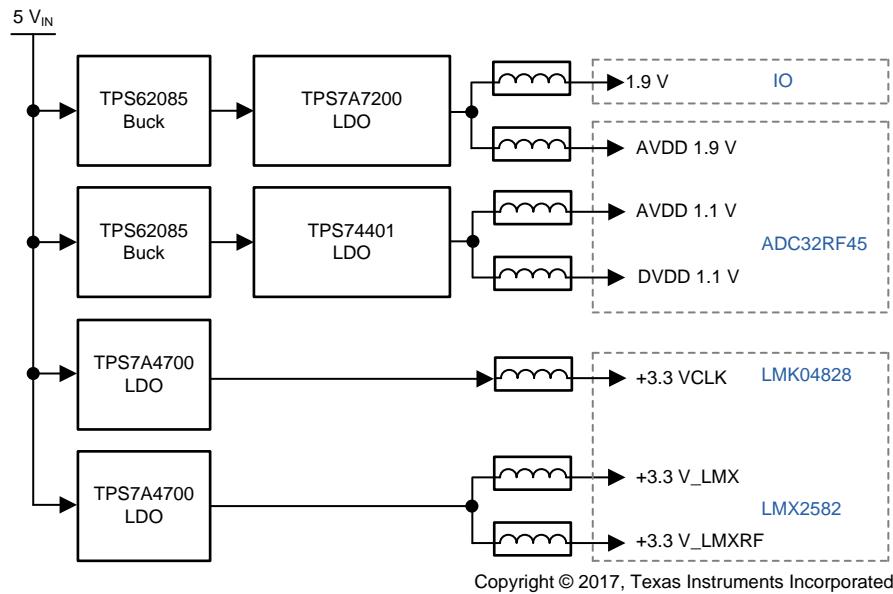


图 3. Power Management Block Diagram

4 Getting Started Hardware and Software

4.1 Required Hardware

The required hardware for the TIDA-01442 design is as follows:

- ADC12DJ3200 EVM
- TSW14J57 EVM
- Signal generator

4.1.1 ADC12DJ3200

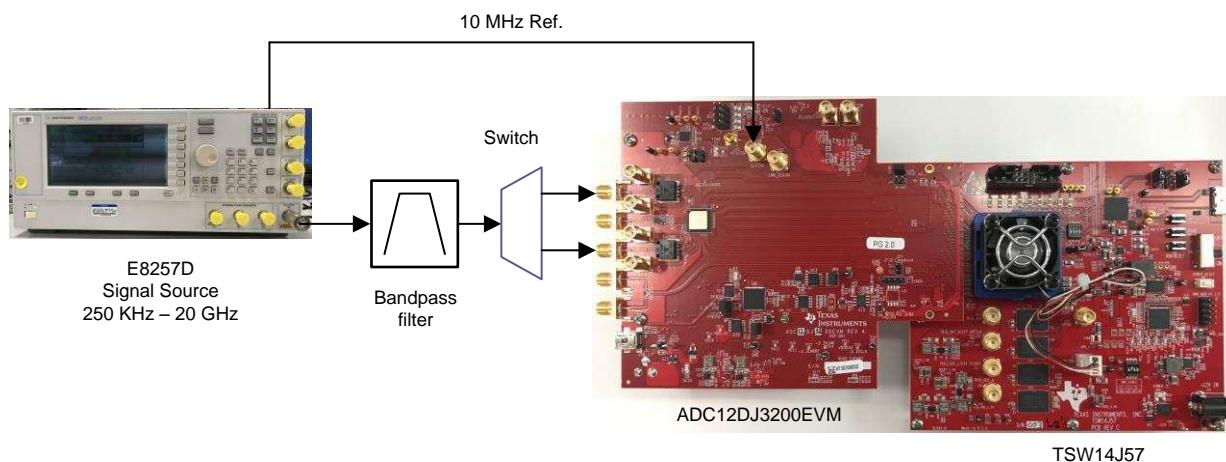
See the ADC12DJ3200EVM tool folder at <http://www.ti.com/tool/ADC12DJ3200EVM> for a detailed description.

4.1.2 TSW14J57

See the TSW14J57 EVM tool folder at <http://www.ti.com/tool/tsw14j57evm> for a detailed description.

4.1.3 Test Setup

The performance measurements of the ADC were taken using the setup shown in [图 4](#). In the setup, a 3.2-GHz clock signal generated by LMX2582 (onboard) is sent to the ADC and LMK04828 (onboard). The LMK04828 is a JESD204B-compliant clock jitter cleaner and is used to provide the SYSREF signals and other required clock signals to the ADC and TSW14J57. The input signal for the ADC is provided by the Agilent Technologies E8257D signal source. The input signal is filtered using a tunable band-pass filter and applied at the channel A or channel B input of the ADC. The input signal and clock are synchronized to each other by feeding a 10-MHz reference signal from the signal source to the LMK04828 device. The ADC12DJ3200 EVM is connected to the TSW14J57 capture card to capture the output digital data of the ADC. The captured data is processed using the High Speed Data Converter (HSDC) Pro software. Both boards are powered by +5-V supplies (through barrel connectors) and connect to a PC through USB cables.



Copyright © 2017, Texas Instruments Incorporated

图 4. Test Setup Diagram

4.2 Software

4.2.1 ADC12DJ3200 GUI

The ADC12DJ3200EVM board must be configured through the ADC12DJ3200 GUI before conversions can be captured. After launching the GUI, the first step is to select the *On-board* option using the drop-down menu under the #1. *Clock Source* field. Then set the clocking frequency to $F_{clk} = 3200\text{ MHz}$ using the drop-down menu under the #2a. *On-board Fclk Selection* (see 图 5). The next step is to select JMODE0 if taking single-channel interleaved measurements or JMODE3 if taking dual-channel measurements. In single-channel interleaved mode, the input single is applied to the single input channel. In this mode, both the rising edge and falling edge of the FCLK are used to sample the input signal, thus making the effective sampling rate 6.4 GSPS with a 3.2-GHz clock. Alternatively, in dual-channel mode, both the input channels are used with each channel to sample an input signal at 3.2 GSPS with a 3.2-GHz clock. The last step is to click the *Program Clocks and ADC* button and wait for the script to finish execution. This step completes the configuration and then the user can launch and configure the HSDC Pro GUI.

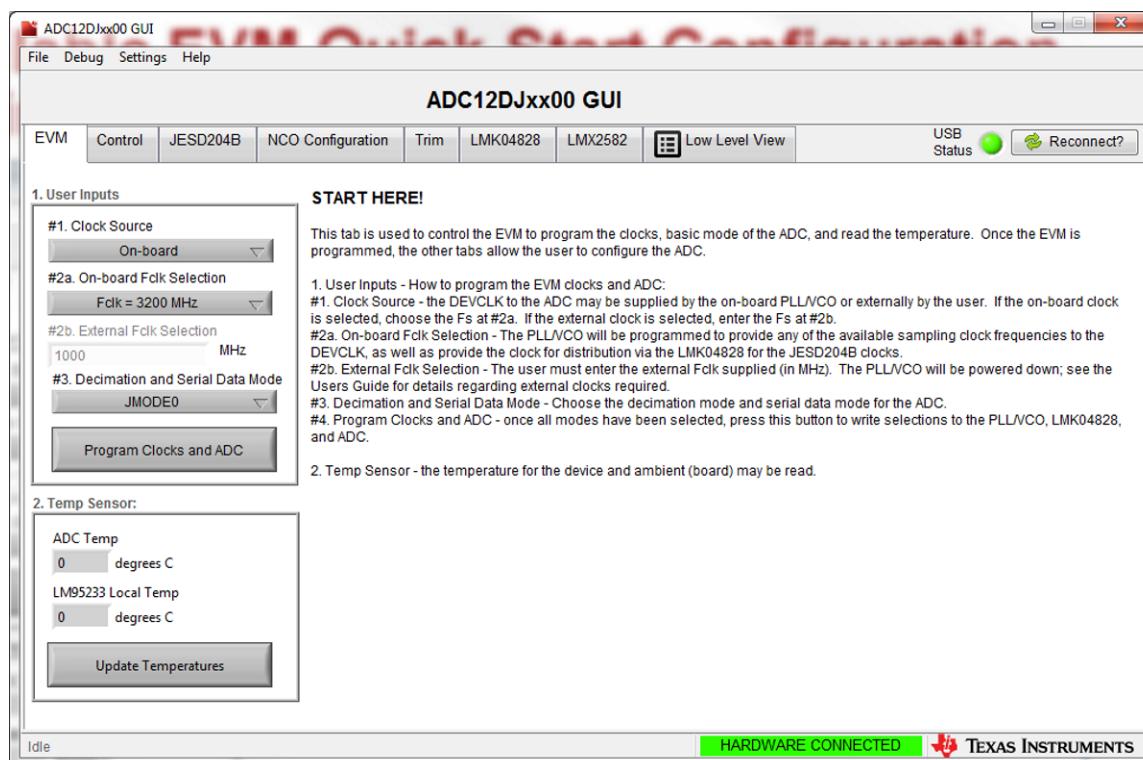


图 5. ADC12DJ3200 GUI—Quick Setup

4.2.2 HSDC Pro GUI

HSDCpro GUI works with a TSW14J57 capture card and is used to process and display data captured from the ADC12DJ3200. Download the HSDC Pro software from <http://www.ti.com/tool/dataconverterpro-sw>. As 图 6 shows, click on the drop-down menu and select "ADC32RF45_LMF_82820". Next set the *ADC Output Data Rate* to "6.4G" for single-channel interleaved mode and "3.2G" for dual-channel mode. The HSDC Pro software is now configured and data can be captured by clicking the *Capture* button.

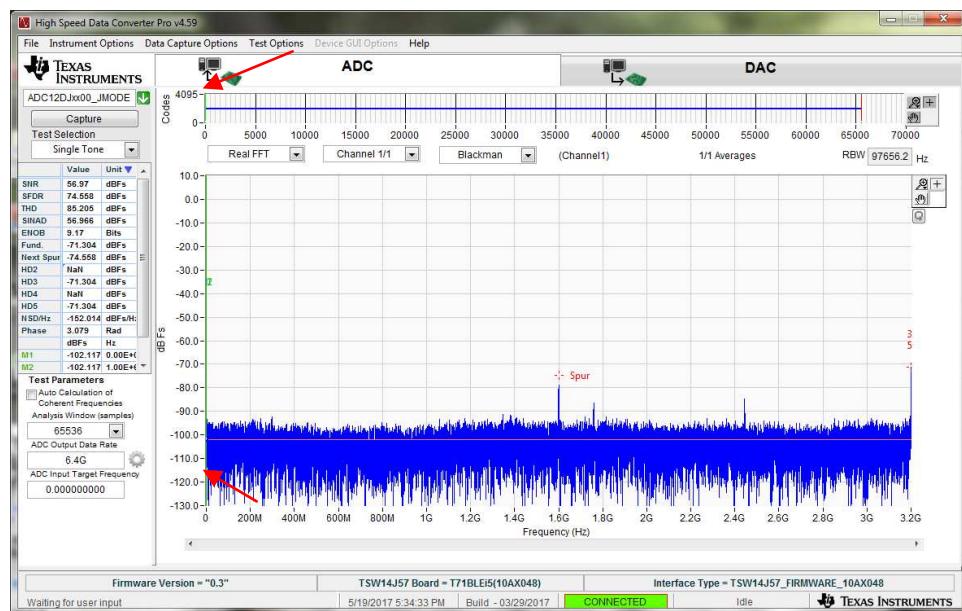


图 6. HSDC Pro GUI—Configuring Device and Sample Rate

图 6 also shows the fast Fourier transform (FFT) of captured data from the ADC12DJ3200EVM board. The HSDC Pro software provides a time domain and frequency domain analysis. The HSDC Pro software also provides single-tone FFT statistic parameters such as signal-to-noise ratio (SNR), spurious free dynamic range (SFDR), total harmonic distortion (THD), signal-to-noise and distortion ratio (SINAD), effective number of bits (ENOB), fundamental tone power, and HD2-5.

5 Testing and Results

A variety of measurements were taken to demonstrate the performance of ADC12DJ3200EVM board. A clean, filtered signal was fed into the ADC12DJ3200EVM board to test the performance and the SNR, HD2, HD3, and other various parameters were measured. The measurements were performed for both the single-channel interleaved mode (6.4 GSPS) and dual-channel mode (3.2 GSPS for each channel). JMODE0 was used for the single-channel interleaved mode. In JMODE0, the digital data from the ADC is sent to the capture card (FPGA) over eight serializer/deserializer (SerDes) lanes with a lane rate of 12.8 Gbps. JMODE3 was used for dual-channel measurements. In JMODE3, the digital data from the ADC is sent to the FPGA over 16 SerDes lanes with half the lane rate of JMODE0, which is 6.4 Gbps.

图 7 显示了 SNR 性能，输入信号为 -1-dBFS，频率从 30 MHz 到 10 GHz。对于单通道交错模式，输入信号应用于通道 A。对于双通道输入测量，输入信号同时应用于通道 A 和通道 B。

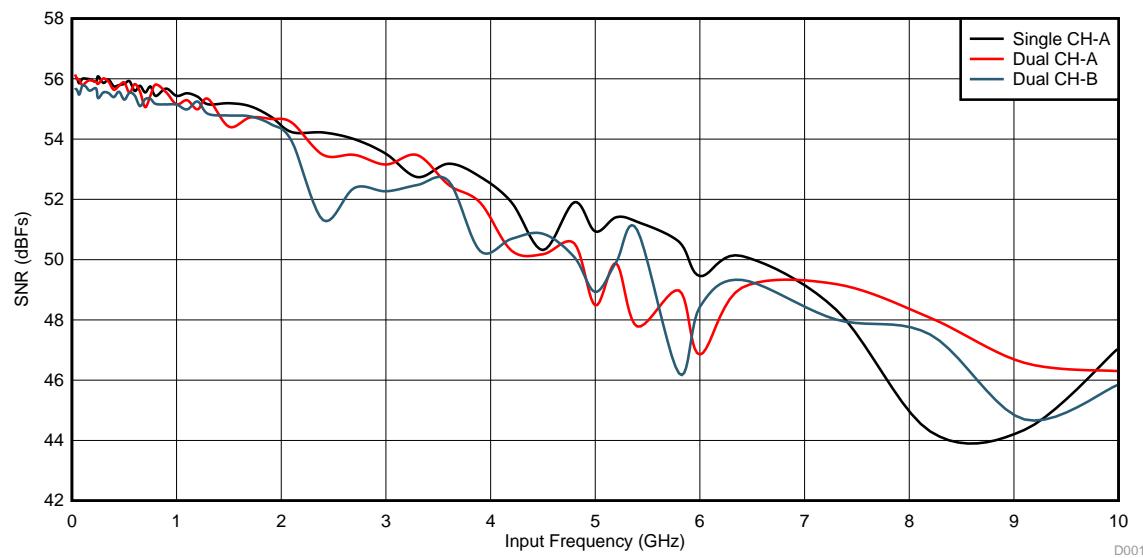


图 7. SNR for Interleaved Single- and Dual-Channel Modes

图 8 显示了 THD 为单通道交错模式和双通道模式。

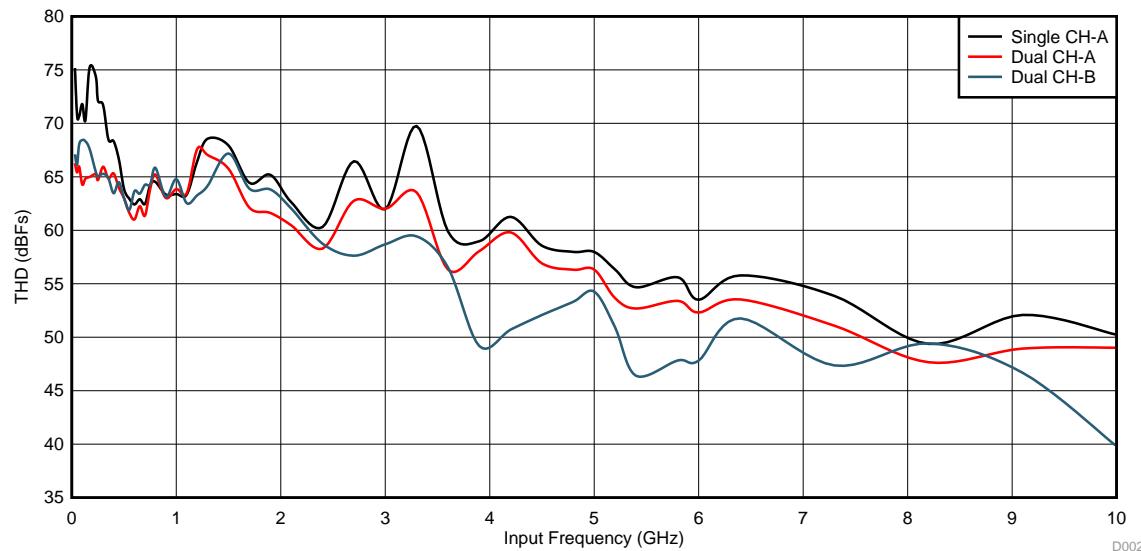


图 8. THD Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

图 9 和 图 10 展示了 HD2 和 HD3 性能，适用于单通道交错模式和双通道模式。

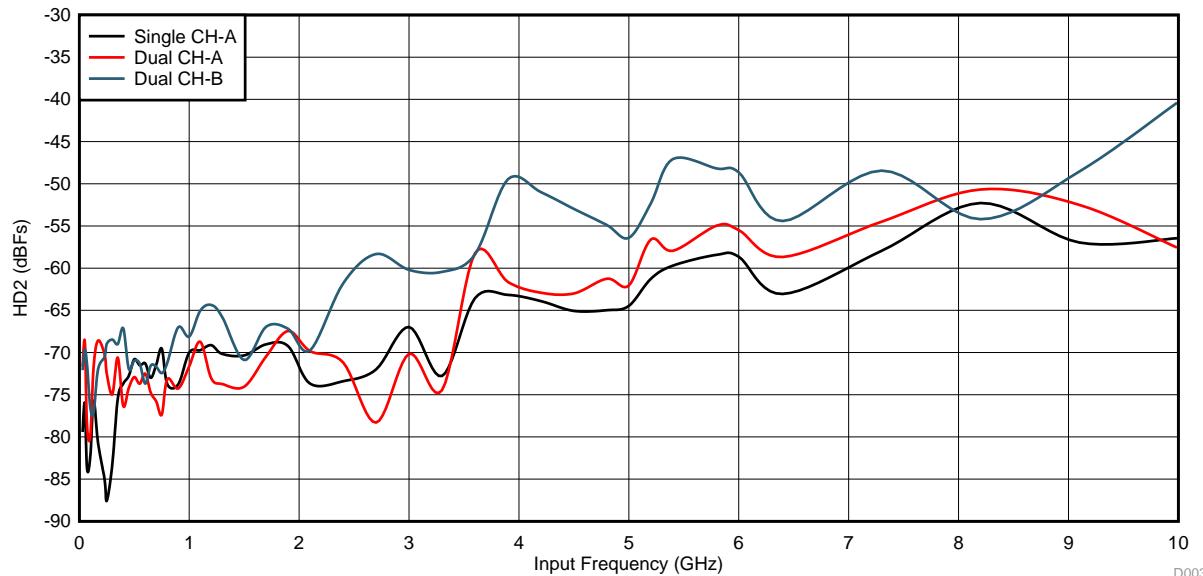


图 9. HD2 Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

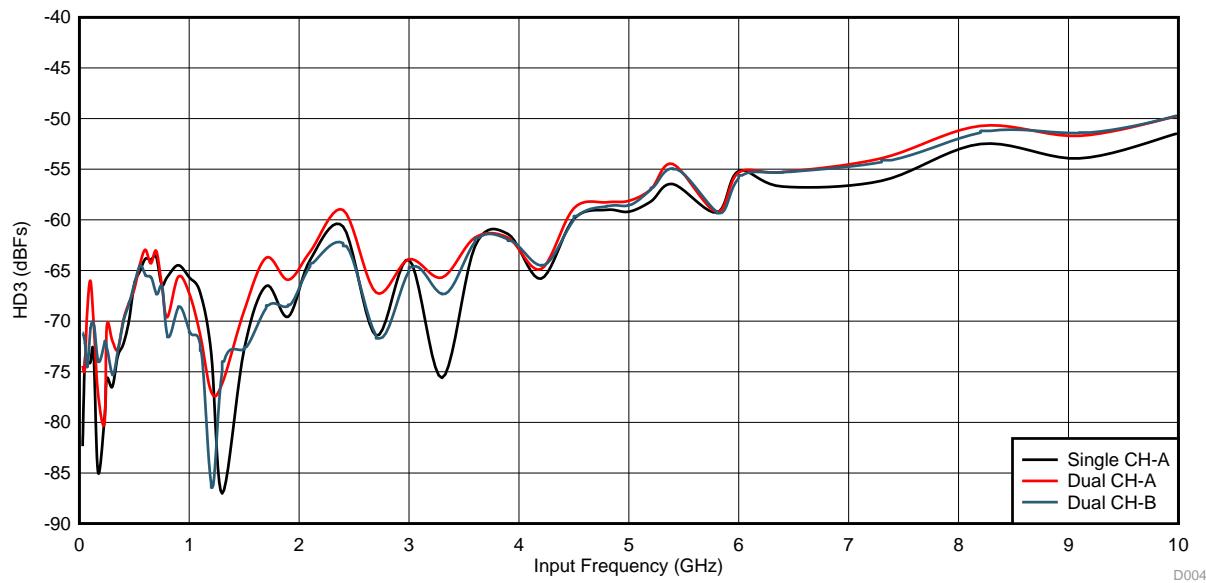


图 10. HD3 Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

图 11 和 图 12 展示了 SFDR 和 SINAD 性能，适用于单通道交错模式和双通道模式。

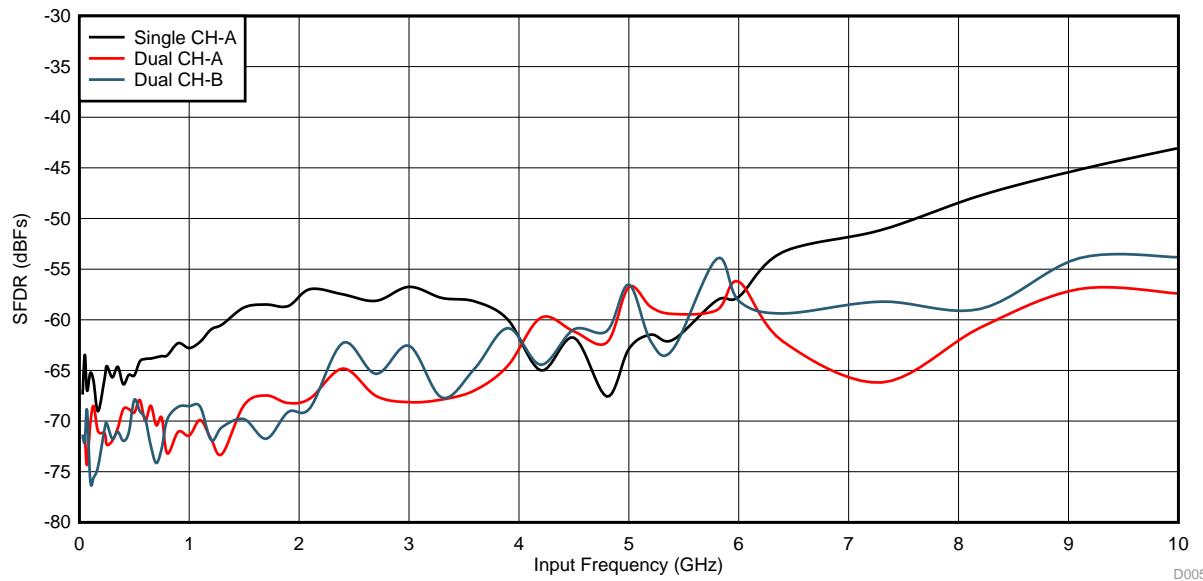


图 11. SFDR Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

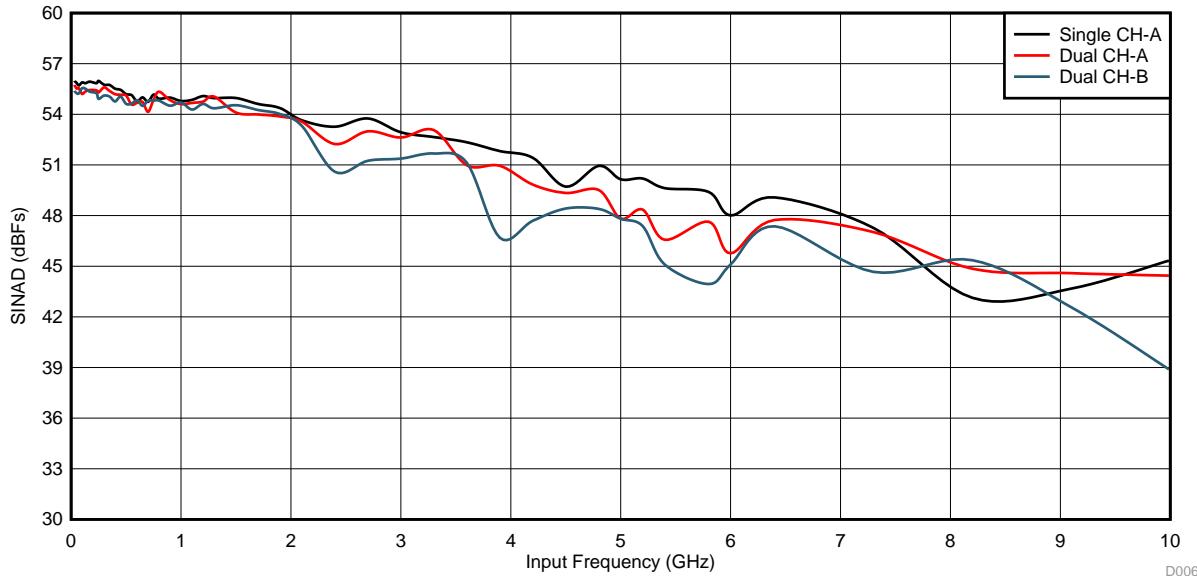


图 12. SINAD Performance for Single-Channel Interleaved Mode and Dual-channel Code

图 13 和 图 14 展示了 S11 和频率响应性能，适用于单通道交错模式和双通道模式。

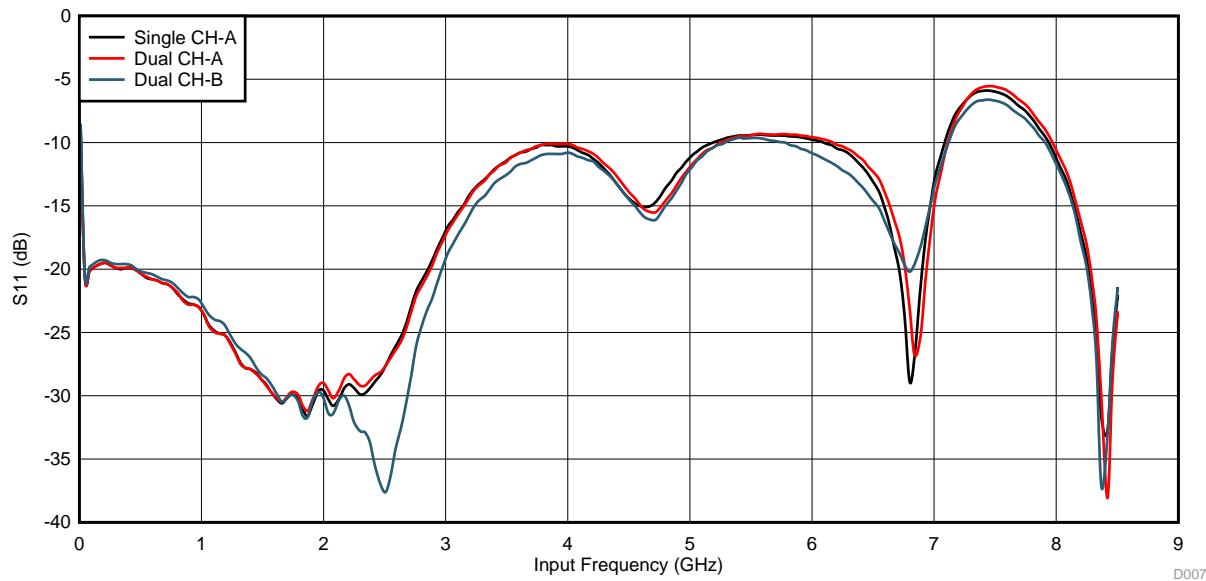


图 13. S11 性能对于单通道交错模式和双通道模式

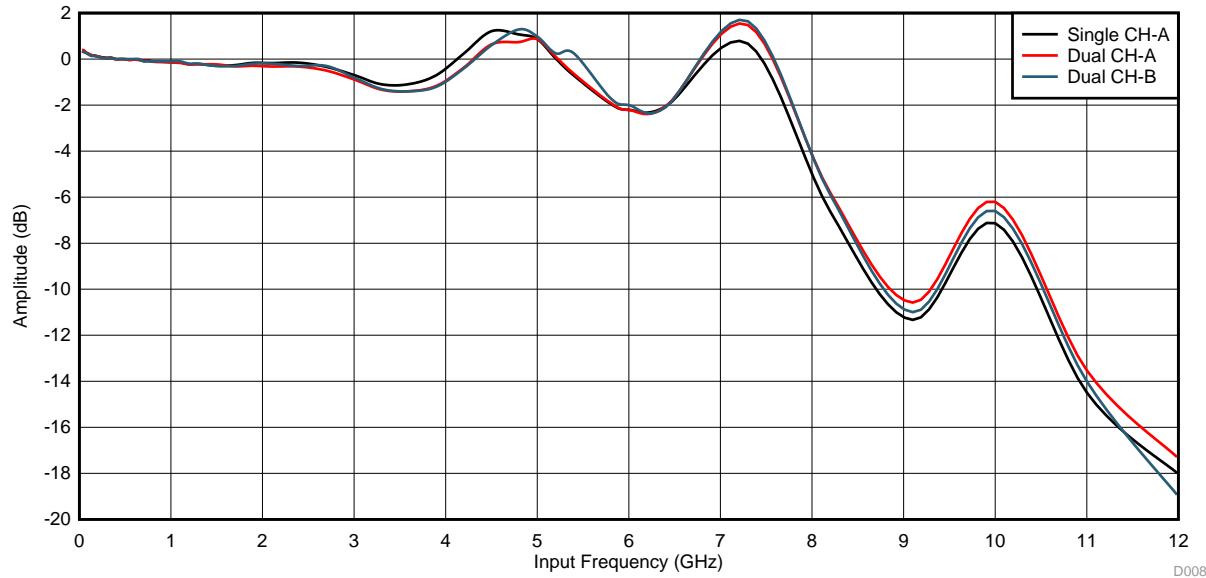


图 14. 频率响应对于单通道交错模式和双通道模式

图 15 显示了双通道模式下的通道对通道隔离性能。

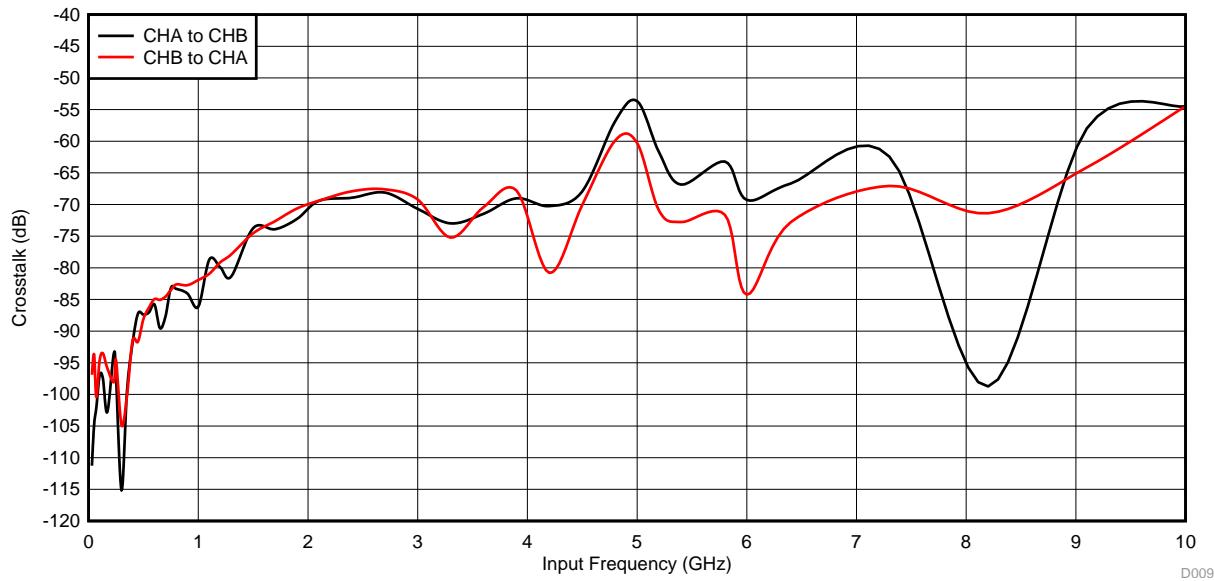


图 15. Crosstalk Performance in Dual-Channel Mode for Channel A and Channel B

The board was modified by replacing both the input baluns with BALH-0009SMG. This balun has a better performance at higher frequencies.

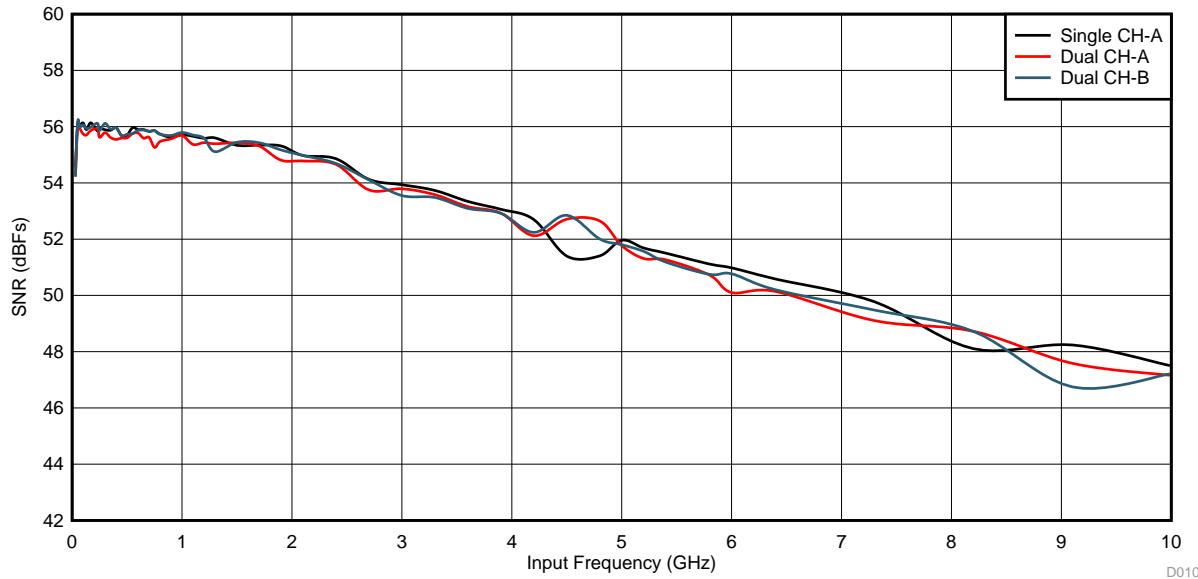


图 16. SNR for Interleaved Single-Channel and Dual-Channel Mode

图 17 显示了 THD 为单通道交织模式和双通道模式。

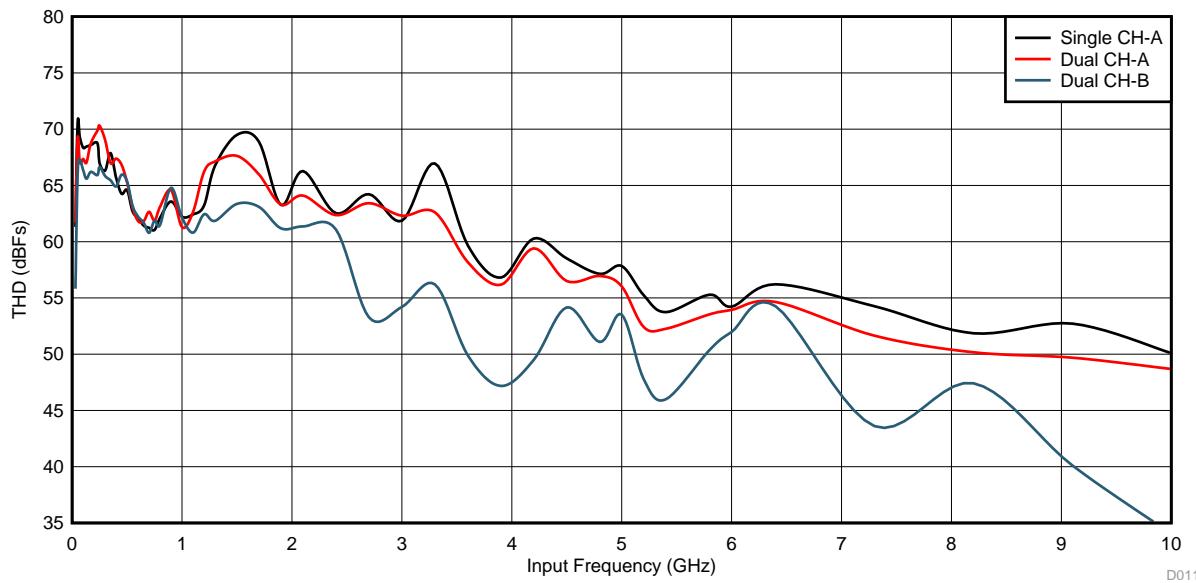


图 17. THD Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

图 18 和 图 19 显示了 HD2 和 HD3 性能，对于单通道交织模式和双通道模式。

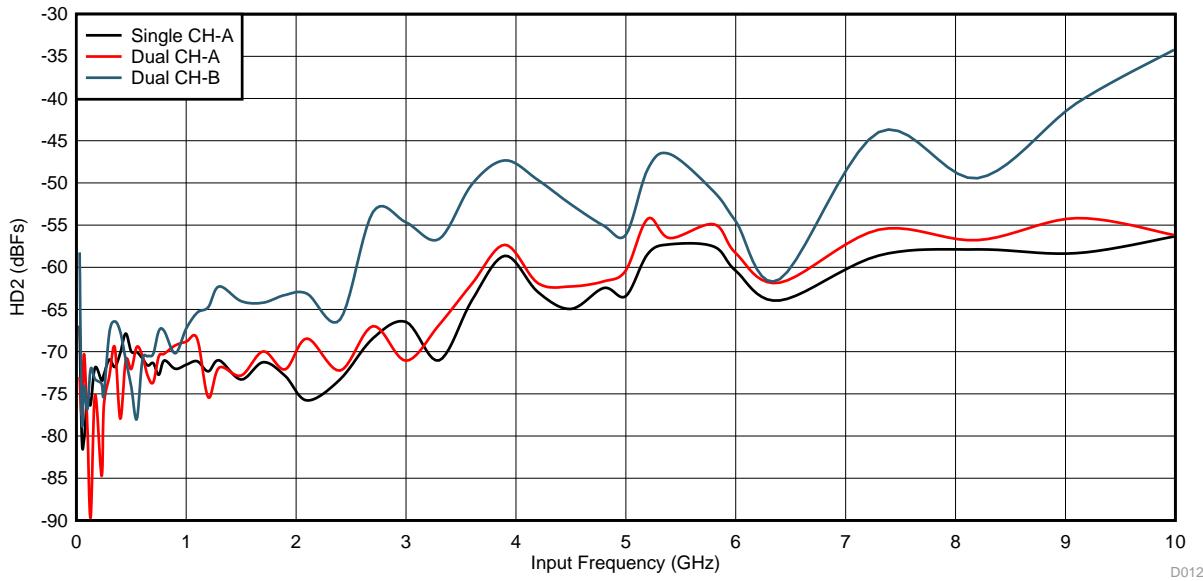


图 18. HD2 Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

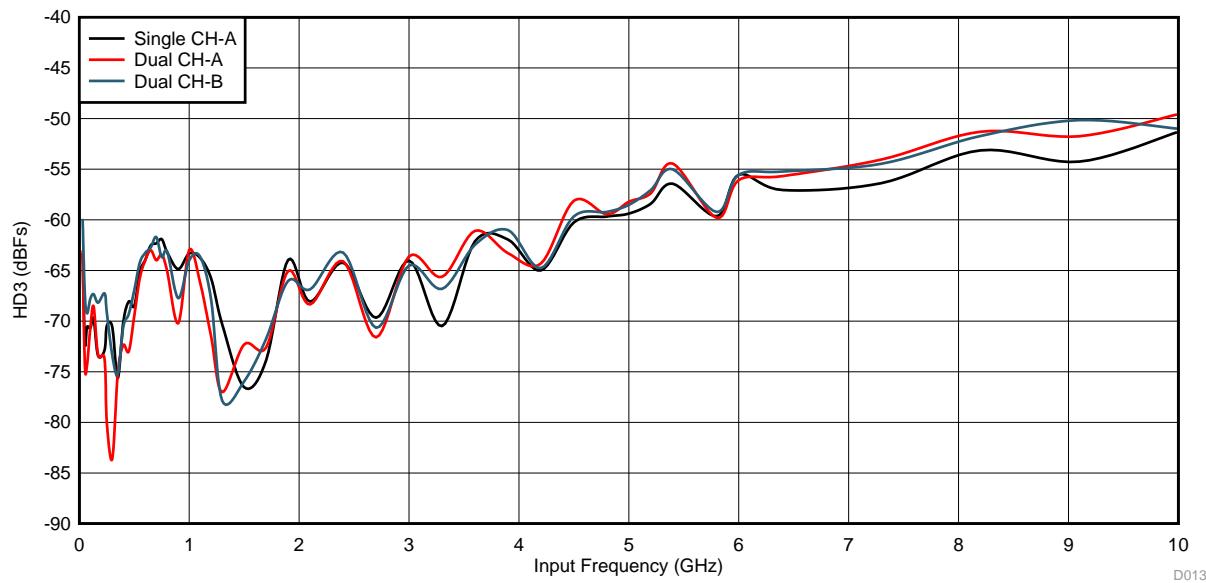


图 19. HD3 Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

图 20 和 图 21 展示了 SFDR 和 SINAD 性能，适用于单通道交错模式和双通道模式。

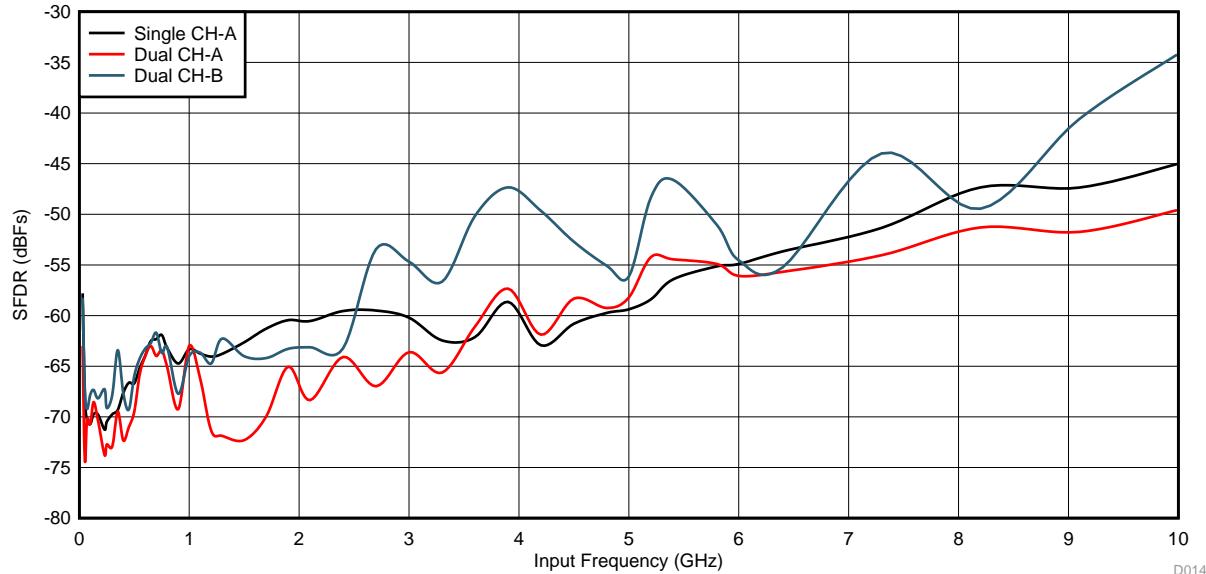


图 20. SFDR Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

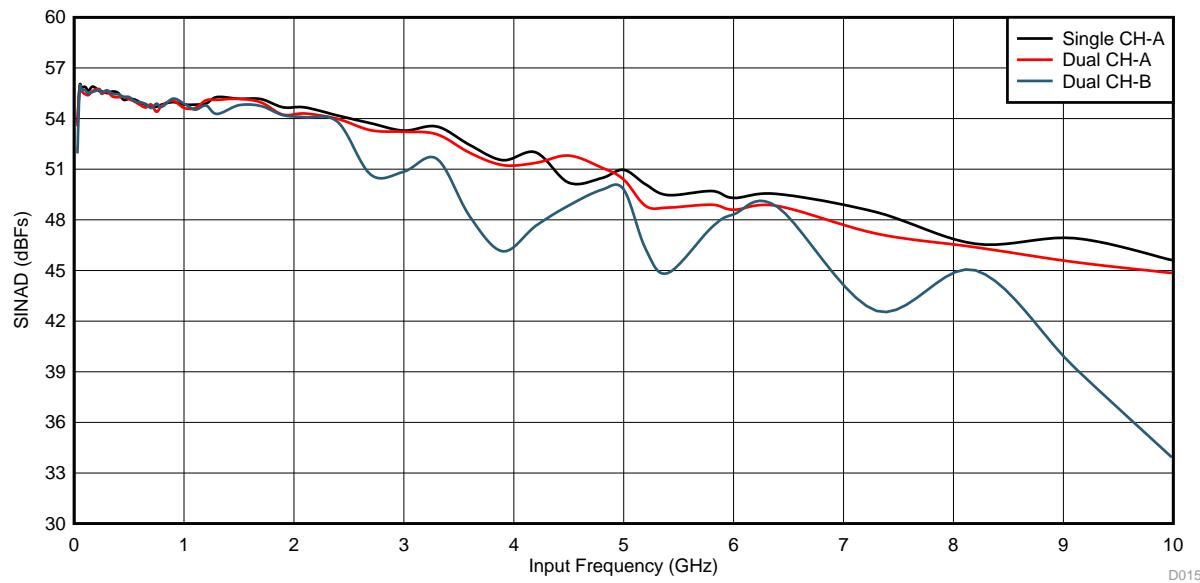


图 21. SINAD Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

图 22 和 图 23 展示了 S11 和频率响应性能，适用于单通道交错模式和双通道模式。

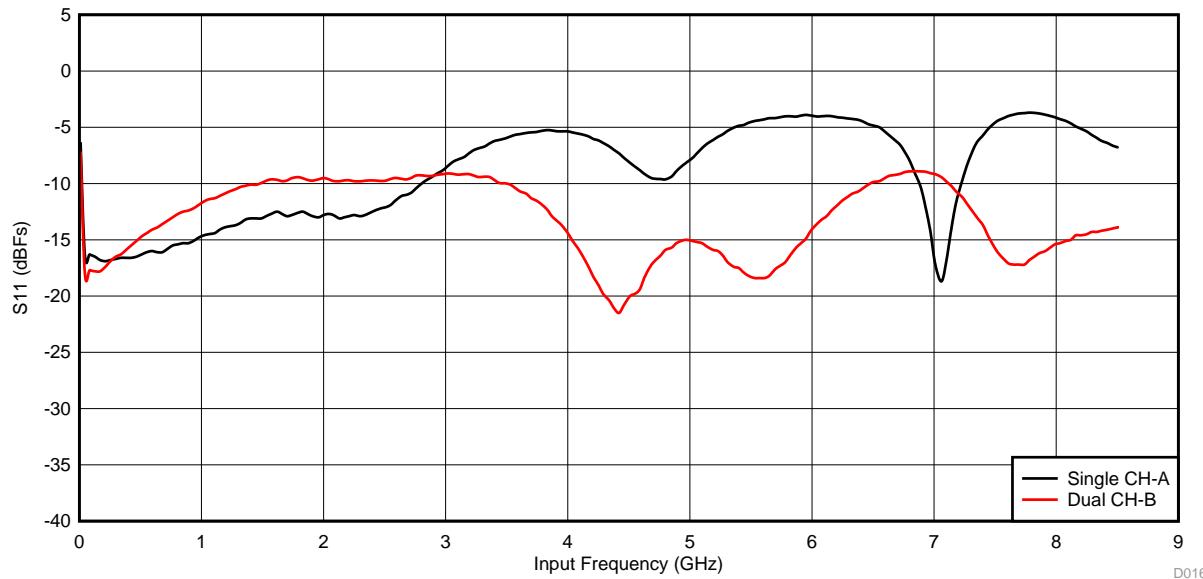


图 22. S11 Performance for Single-Channel Interleaved Mode and Dual-Channel Mode

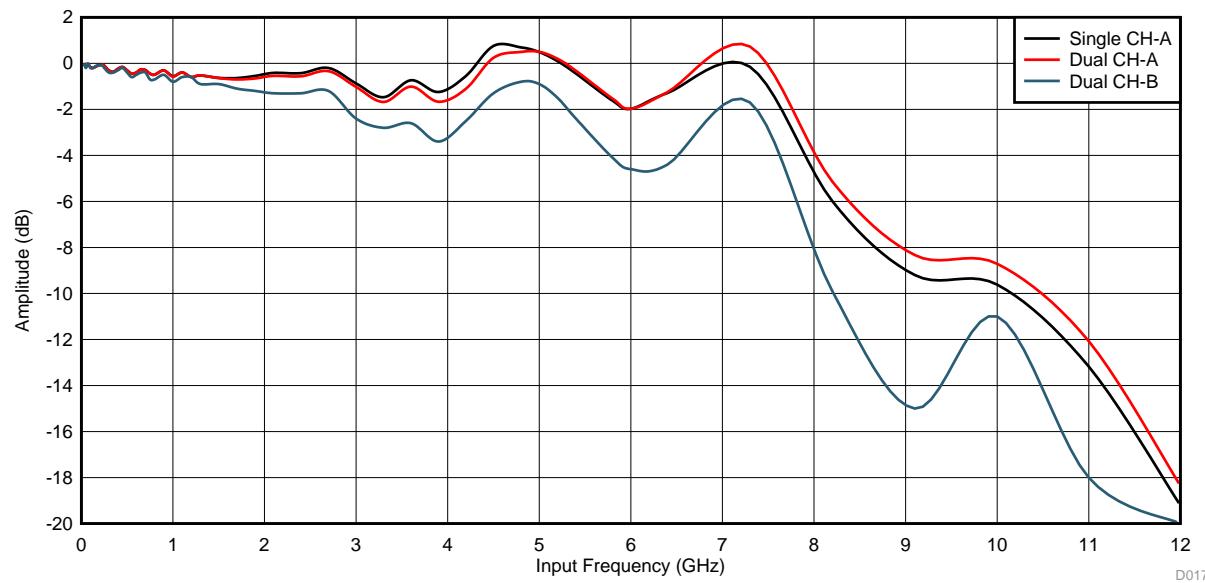


图 23. Frequency Response for Single-Channel Interleaved Mode and Dual-Channel Mode

图 24 shows the channel-to-channel isolation performance for dual-channel mode.

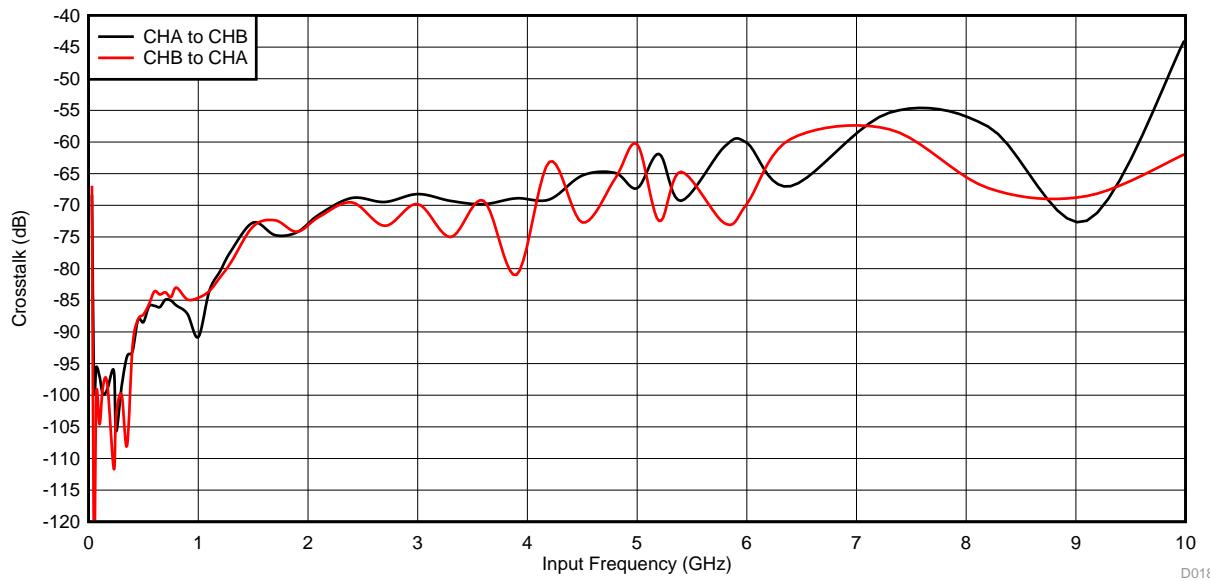


图 24. Crosstalk Performance in Dual-Channel Mode for Channel A and Channel B

6 Design Files

6.1 Schematics

To download the schematics, see the design files at [TIDA-01442](#).

6.2 Bill of Materials

To download the bill of materials (BOM), see the design files at [TIDA-01442](#).

6.3 PCB Layout Recommendations

6.3.1 Layout Prints

To download the layer plots, see the design files at [TIDA-01442](#).

6.4 PCB Project

To download the Altium project files, see the design files at [TIDA-01442](#).

6.5 Gerber Files

To download the Gerber files, see the design files at [TIDA-01442](#).

6.6 Assembly Drawings

To download the assembly drawings, see the design files at [TIDA-01442](#).

7 Software Files

To download the software files, see the design files at [TIDA-01442](#).

8 商标

All trademarks are the property of their respective owners.

9 About the Author

NEERAJ GILL is an application engineer in high-speed catalog converters group at Texas Instruments. Gill received his BSEE from University of New Hampshire in 2011 and then his Masters in Electrical Engineering also from University of New Hampshire in 2013.

有关 TI 设计信息和资源的重要通知

德州仪器 (TI) 公司提供的技术、应用或其他设计建议、服务或信息，包括但不限于与评估模块有关的参考设计和材料（总称“TI 资源”），旨在帮助设计人员开发整合了 TI 产品的应用；如果您（个人，或如果是代表贵公司，则为贵公司）以任何方式下载、访问或使用了任何特定的 TI 资源，即表示贵方同意仅为该等目标，按照本通知的条款进行使用。

TI 所提供的 TI 资源，并未扩大或以其他方式修改 TI 对 TI 产品的公开适用的质保及质保免责声明；也未导致 TI 承担任何额外的义务或责任。TI 有权对其 TI 资源进行纠正、增强、改进和其他修改。

您理解并同意，在设计应用时应自行实施独立的分析、评价和判断，且应全权负责并确保应用的安全性，以及您的应用（包括应用中使用的所有 TI 产品）应符合所有适用的法律法规及其他相关要求。你就您的应用声明，您具备制订和实施下列保障措施所需的一切必要专业知识，能够（1）预见故障的危险后果，（2）监视故障及其后果，以及（3）降低可能导致危险的故障几率并采取适当措施。您同意，在使用或分发包含 TI 产品的任何应用前，您将彻底测试该等应用和该等应用所用 TI 产品的功能而设计。除特定 TI 资源的公开文档中明确列出的测试外，TI 未进行任何其他测试。

您只有在为开发包含该等 TI 资源所列 TI 产品的应用时，才被授权使用、复制和修改任何相关单项 TI 资源。但并未依据禁止反言原则或其他法理授予您任何 TI 知识产权的任何其他明示或默示的许可，也未授予您 TI 或第三方的任何技术或知识产权的许可，该等产权包括但不限于任何专利权、版权、屏蔽作品权或与使用 TI 产品或服务的任何整合、机器制作、流程相关的其他知识产权。涉及或参考了第三方产品或服务的信息不构成使用此类产品或服务的许可或与其相关的保证或认可。使用 TI 资源可能需要您向第三方获得对该等第三方专利或其他知识产权的许可。

TI 资源系“按原样”提供。TI 兹免除对 TI 资源及其使用作出所有其他明确或默认的保证或陈述，包括但不限于对准确性或完整性、产权保证、无屡发故障保证，以及适销性、适合特定用途和不侵犯任何第三方知识产权的任何默认保证。

TI 不负责任何申索，包括但不限于因组合产品所致或与之有关的申索，也不为您辩护或赔偿，即使该等产品组合已列于 TI 资源或其他地方。对因 TI 资源或其使用引起或与之有关的任何实际的、直接的、特殊的、附带的、间接的、惩罚性的、偶发的、从属或惩戒性损害赔偿，不管 TI 是否获悉可能会产生上述损害赔偿，TI 概不负责。

您同意向 TI 及其代表全额赔偿因您不遵守本通知条款和条件而引起的任何损害、费用、损失和/或责任。

本通知适用于 TI 资源。另有其他条款适用于某些类型的材料、TI 产品和服务的使用和采购。这些条款包括但不限于适用于 TI 的半导体产品 (<http://www.ti.com/sc/docs/stdterms.htm>)、**评估模块** 和样品 (<http://www.ti.com/sc/docs/samptersms.htm>) 的标准条款。

邮寄地址：上海市浦东新区世纪大道 1568 号中建大厦 32 楼，邮政编码：200122
Copyright © 2018 德州仪器半导体技术（上海）有限公司